

Notice of References Cited	Application/Control No. 10/598,347		Applicant(s)/Patent Under Reexamination LI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0080342 A1	04-2005	Gilreath et al.	600/476
*	B	US-2003/0020810 A1	01-2003	Takizawa et al.	348/68
*	C	US-2003/0043263 A1	03-2003	Glukhovsky et al.	348/61
*	D	US-2004/0254455 A1	12-2004	Iddan, Gavriel J.	600/424
*	E	US-2003/0023150 A1	01-2003	Yokoi et al.	600/300
*	F	US-2004/0122315 A1	06-2004	Krill, Jerry A.	600/437
*	G	US-2002/0147008 A1	10-2002	Kallio, Janne	455/426
*	H	US-2005/0080342 A1	04-2005	Gilreath et al.	600/476
*	I	US-2002/0171669 A1	11-2002	Meron et al.	345/619
*	J	US-2004/0092825 A1	05-2004	Madar et al.	600/473
*	K	US-2003/0158503 A1	08-2003	Matsumoto, Shinya	600/593
*	L	US-2007/0268280 A1	11-2007	Fujita et al.	345/204
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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